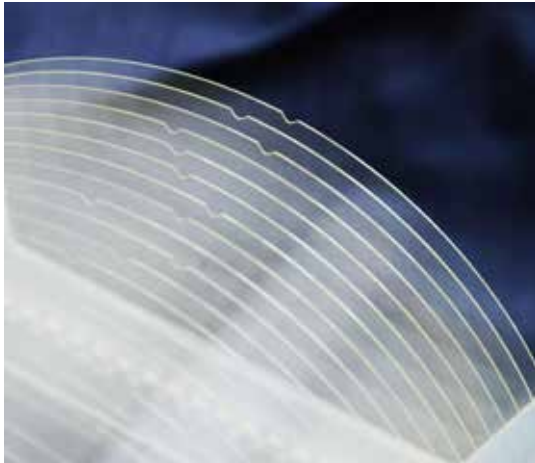


# Glass Inspect



## ParticleInspect - The Optimal AOI Particle Counter Solution for Glass Wafers



Dr. Schenk ParticleInspect for glass wafers is designed for high-speed particle detection of bare glass wafers and glass wafers with AR coating.

High resolution scanning for smallest particles such as dust, hair, fibers or adhered glass chips will ensure that sources of contamination can be identified and addressed before large production losses occur.

ParticleInspect for glass wafers can differentiate clearly between A-side and B-side particles, an exclusive benefit of the Dr. Schenk inspection. The system comprises a complete stand alone AOI solution with drawer handling.

### Worldwide installations, great experience

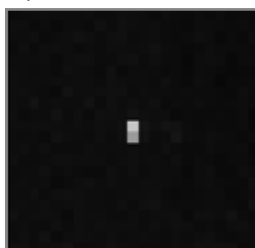
Dr. Schenk can look back at more than 30 years of experience in the development, installation and constant improvement in the field of glass inspection. Customers worldwide have increased their productivity and reduced their waste with the automatic optical glass wafer inspection of ParticleInspect.

Only a highly specialized system can fulfill all expectations of customers in this demanding market and keep pace with future developments without needing to invest in other systems.

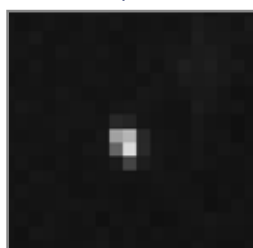


*ParticleInspect for Glass Wafers Solution by Dr. Schenk*

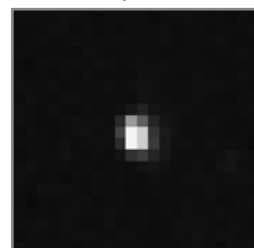
*Particles 0.3  $\mu\text{m}$  (optional)*



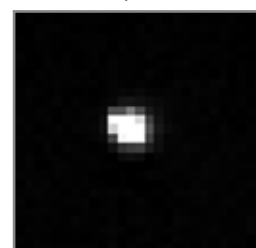
*Particles 1  $\mu\text{m}$*



*Particles 3  $\mu\text{m}$*



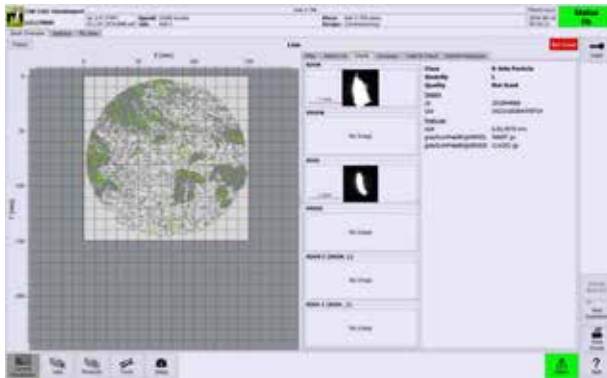
*Particles 5  $\mu\text{m}$*



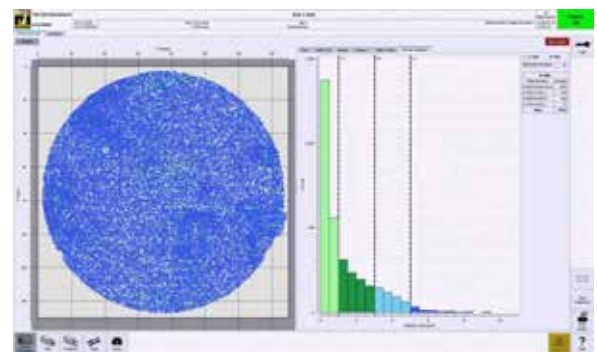
Glass Wafers

## KEY FEATURES

- Dr. Schenk TDI camera with 256 lines and high resolution (9 Mega Pixel)
- Proprietary ultra-bright LED illumination technology in reflection mode for superior sensitivity on top and bottom surface down to 1  $\mu\text{m}$  particle size (0.3  $\mu\text{m}$  particle size optional)
- A- and B-side discrimination down to 325  $\mu\text{m}$  glass thickness
- Automatic adaptation to different glass wafer thickness by inspection recipe
- Setup time for different glass wafer diameter: < 1 hour
- Sensitivity adjustable (low and high sensitivity mode) by customer according to the minimum size of particles that are of interest
- New generation of glass wafer handling: with high speed inspection cycle time down to 4 sec



Defect map overview after particle scan



Particle Histogram separated by A-side and B-side

### About Dr. Schenk

Dr. Schenk GmbH offers inspection and measurement solutions for automated quality assurance and production process control - a key success factor in the making and converting of many materials, e.g. plastics, textile materials, nonwovens, paper, metal, or glass, for a multitude of markets like display glass, automotive, packaging, medical, renewable energy, and many more.

From modular standard units to highly customized systems – Dr. Schenk's solutions have your material in focus!

## CONTACT

Dr. Schenk GmbH Industriemesstechnik

### Headquarters

Bussardstr. 2  
82166 Graefelfing  
GERMANY

Phone: +49-89-85695-0  
Fax: +49-89-85695-200

For more Dr. Schenk locations and regional sales & service partners go to:  
[www.dr.schenk.com/contact.html](http://www.dr.schenk.com/contact.html)

